



INFORMATION DISCLOSURE STATEMENT BY APPLICANT			Application Number	10/649,251	
			Filing Date	August 26, 2003	
			First Named Inventor	Gregory R. Hanson et al.	
			Group Art Unit	2877	
			Examiner Name	Connolly, Patrick J	
Sheet	1	of	2	Attorney Docket Number	UBAT1510
NON-PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No.	Citation			
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Examiner Signature	PATRICE CONNOLLY			Date Considered	09.21.2005

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PTC		Volkl, E., et al., "The Extended Fourier Algorithm. Application in Discrete Optics and Electron Holography", HIGH TEMPERATURE MATERIALS LABORATORY, July 1994.		
Examiner Signature	PATRICK CONNOLLY		Date Considered	08.21.2005